

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicants : TANAKA, Shoji
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OGINO, Tomotaka

International Appl. No. : PCT/JP2004/016125

International Filing Date : 29, October 2004

For : MAKEUP SIMULATION PROGRAM, MAKEUP
SIMULATION DEVICE, AND MAKEUP
SIMULATION METHOD

MS PCT
Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

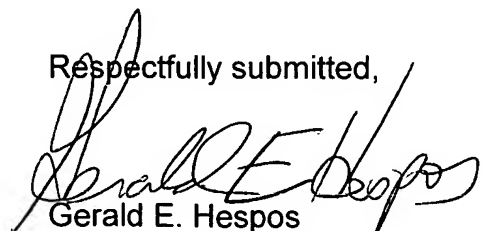
INFORMATION DISCLOSURE STATEMENT

Sir:

This Information Disclosure Statement includes a copy of Form PTO-1449 that identifies five Japanese references and one non-patent publication. Copies of the identified references are attached as well along with English language Abstracts. The relevancy of JP 2003-44837 is explained on page 1 of the subject application. The relevancy of JP 2003-216931 is described on page 63 of the application. The other references were cited in the International Search Report.

The Examiner is requested to consider these references during the examination and to make the references of record.

Respectfully submitted,



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INFORMATION DISCLOSURE CITATION
(Use several sheets if necessary)

Docket Number (Optional)

P1510US

Application Number

10/583619

Applicant(s)

Shoji Tanaka et al.

Filing Date

Concurrently herewith

Group Art Unit

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U.S. PATENT DOCUMENTS

*EXAMINER INITIAL	REF	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE

U.S. PATENT APPLICATION PUBLICATIONS

*EXAMINER INITIAL	REF	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE

FOREIGN PATENT DOCUMENTS

	REF	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	Translation	
							YES	NO
		9-73559	1997	Japan				✓
		11-143352	1999	Japan				✓
		2000-194835	2000	Japan				✓
		2003-44837	2003	Japan				✓
		2003-216931	2003	Japan				✓

OTHER DOCUMENTS

(Including Author, Title, Date, Pertinent Pages, Etc.)

		"Real Time Makeup Simulator" - Takao Furukawa et al., Dai 19 Kai Sensing Forum Shiryo, September 17, 2002, 19th, pgs. 53-58.

EXAMINER

DATE CONSIDERED

EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP Section 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.